



Non-destructive Evaluation for Products and Processes

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Message from the Guest Editors

Dear Colleagues,

In recent years, although NDE methods and SHM systems have become increasingly researched, further efforts must be made to enhance their use in real engineering applications and industrial contexts.

This Special Issue aims to collate recent contributions to the research on NDE methods and SHM systems, providing methods for advancing these systems, as well as the assessment and monitoring of products and processes; innovative aspects about their application in different engineering fields and details about the development of modelling techniques to support the design and the use of such methods.

The potential topics of this Special Issue include, but are not limited to:

- NDE methods;
- SHM systems;
- Numerical modelling to support the design of NDE methods and SHM systems;
- SHM and NDE for maintenance management and repair operations;
- Anomaly diagnosis and prognosis;
- Measurements and processing algorithms for the identification and characterization of anomalies.





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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